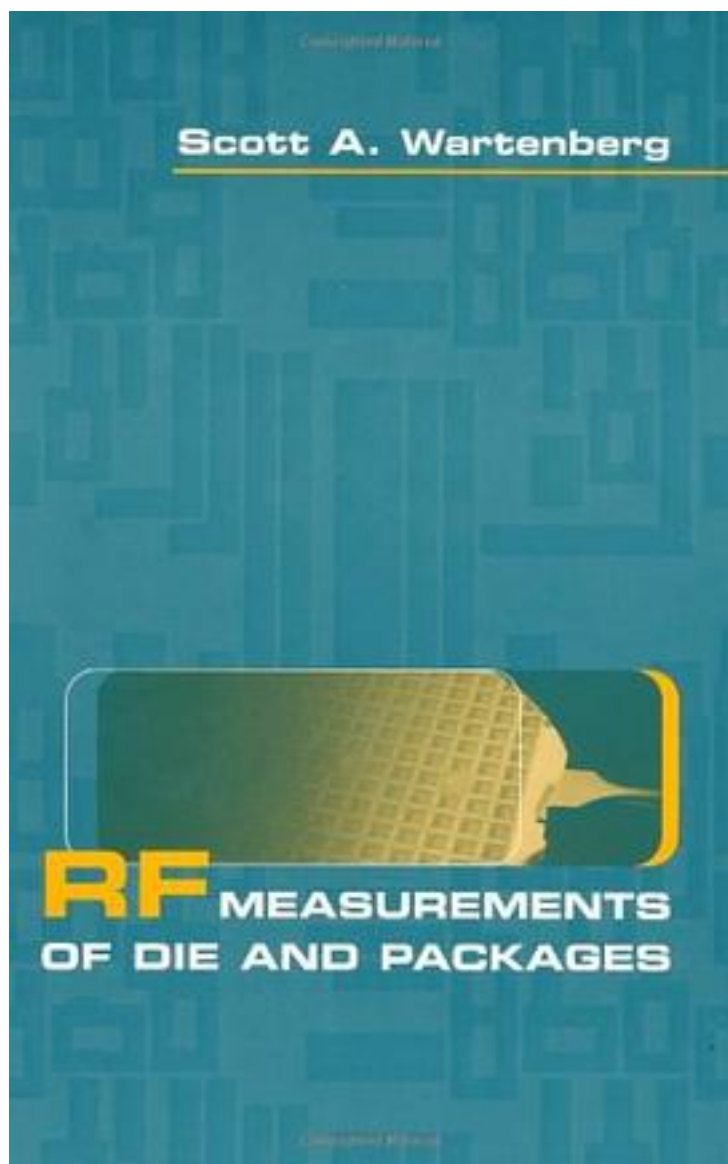


RF Measurements of Die and Packages



[RF Measurements of Die and Packages_ 下载链接1](#)

著者:Wartenberg, Scott A.

出版者:Artech House on Demand

出版时间:

装帧:HRD

isbn:9781580532730

The explosion in the wireless industry, coupled with the higher frequencies in today's digital integrated circuits (IC) has made vital the need for accurate IC testing. This is the first book dedicated to the issues surrounding RFIC testing. This ground breaking work enables professionals to perform high-accuracy RF measurements of die and packages in the RF test lab. This timely volume defines the essential elements in an RF system, explains where errors can be found in such a system and shows how to mathematically remove them with calibration.

作者介绍:

目录:

[RF Measurements of Die and Packages_ 下载链接1](#)

标签

RF

评论

[RF Measurements of Die and Packages_ 下载链接1](#)

书评

[RF Measurements of Die and Packages_ 下载链接1](#)